

presents

Get the most out of your measurement with NI hardware



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Romandie LabVIEW User Group Meeting July 9, 2024

Who are we ?



Custom development services & solutions for 30 years

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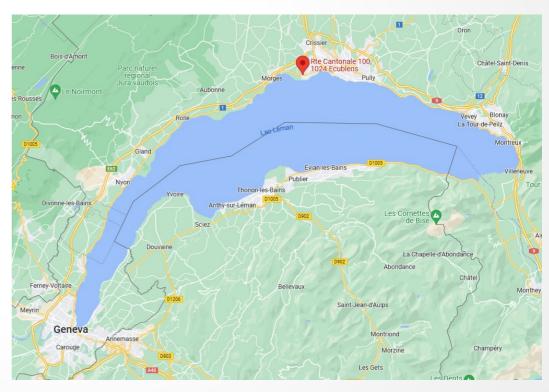
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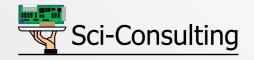


9th July 2024

Romandie LabVIEW User Group

Content

- Use of COTS HW is generally optimal for prototyping, NI products are great for this
- Sometimes cost of HW already becomes an issue for medium scale deployments
- There are ways to address this and deploy NI-based systems with optimized costs without compromising performance, versatility and ease of prototyping
- Here we present a small selection of them



Analog inputs

Multifunction devices

USB X Series

PXI X Series

Most often ±10V analog inputs, with gains







Analog inputs

C Series include signal conditioning :

- ±10V Voltage
- Current ±20mA
- Thermocouple
- RTD
- Strain gauge ... and more



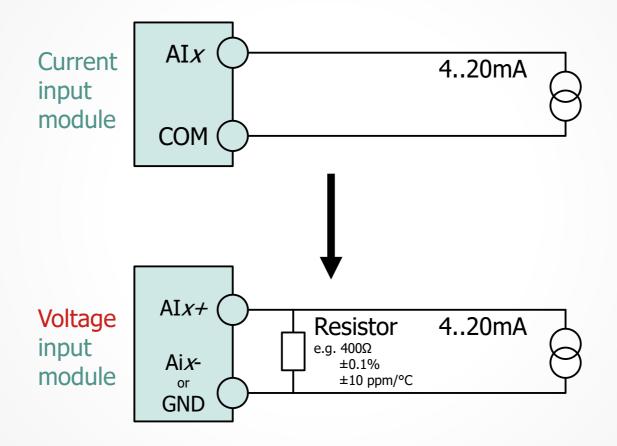






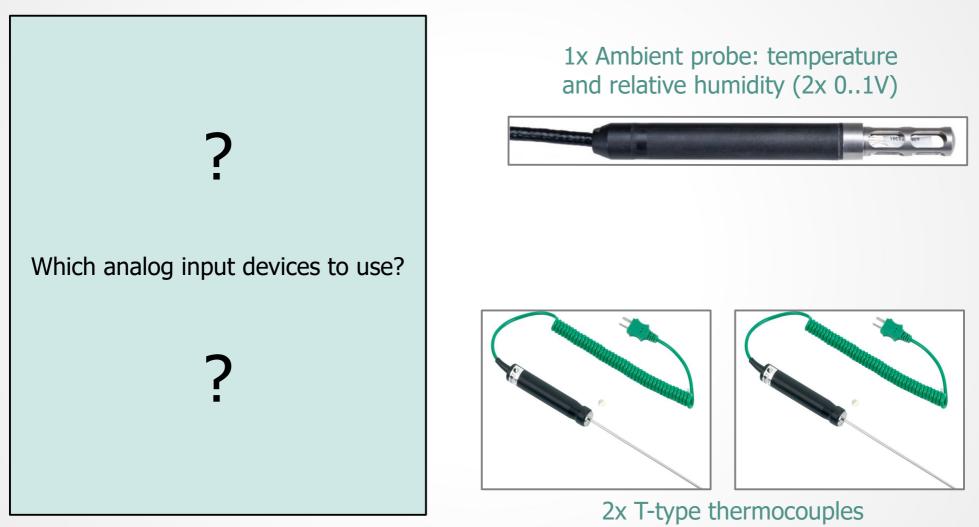
Converting signal conditioning

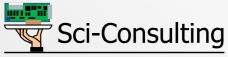
From 4..20mA sensor to voltage module



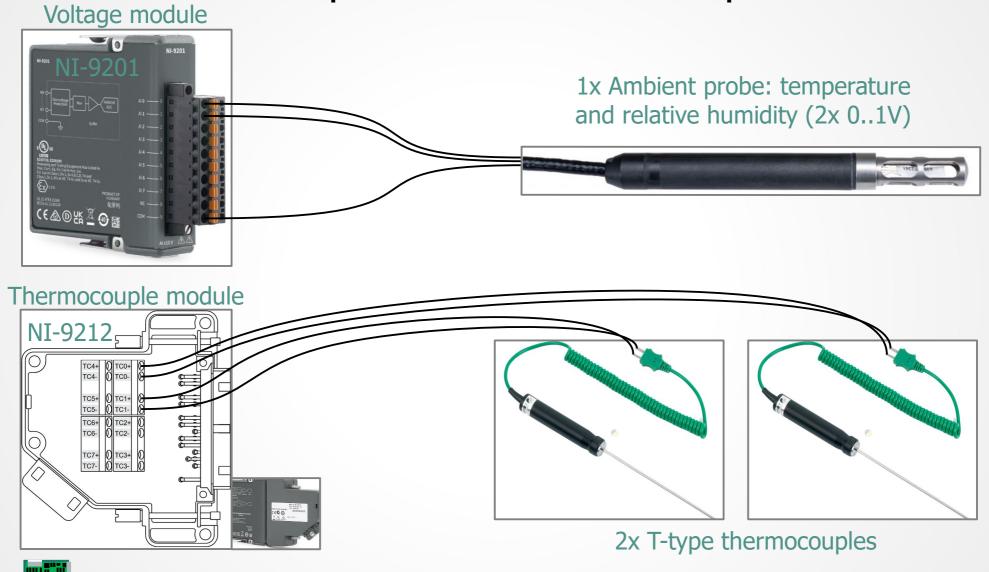


2x thermocouples and 1x ambient probe





2x thermocouples and 1x ambient probe

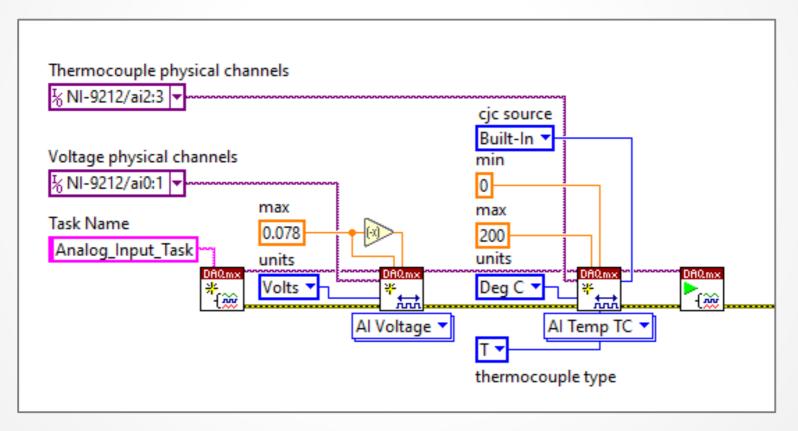


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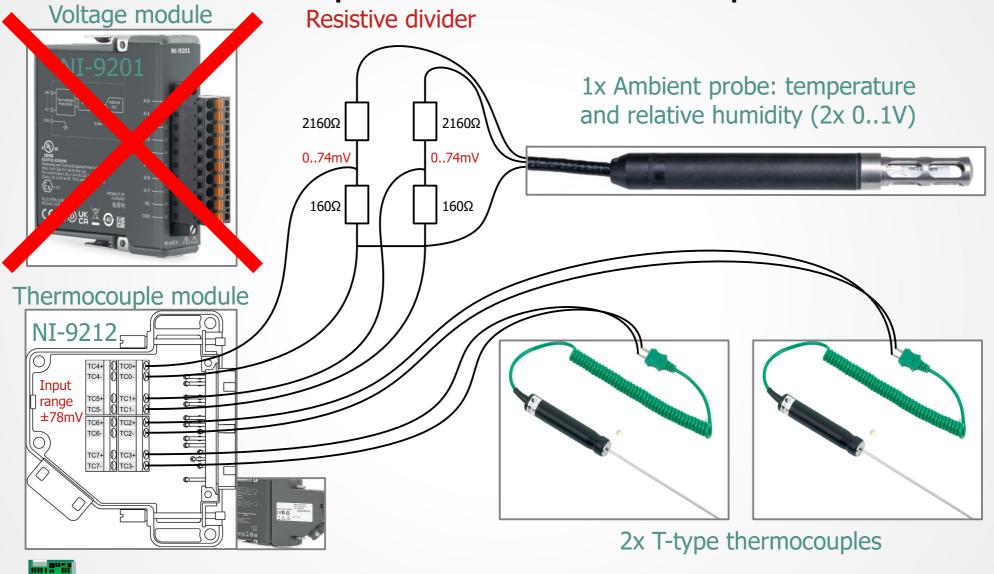
Thermocouple modules can also measure raw voltage

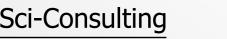
With DAQmx driver, simply configure as separate channels of different types in same task



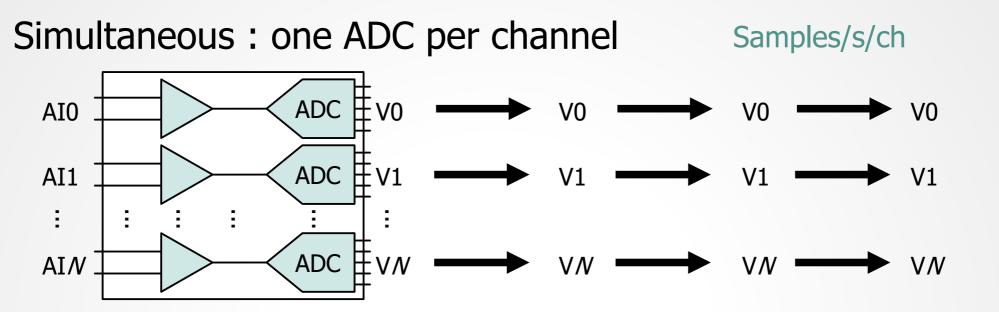


2x thermocouples and 1x ambient probe

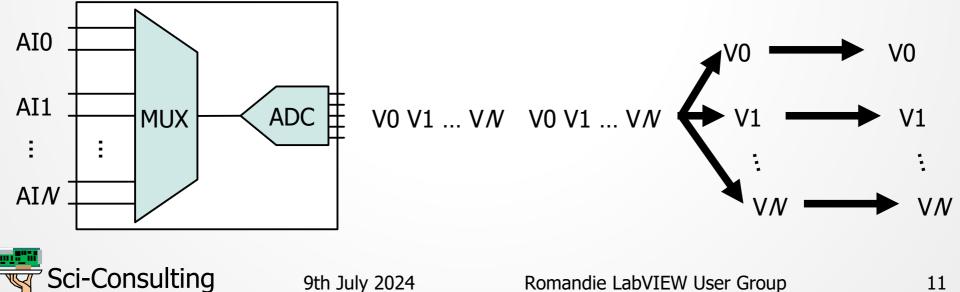




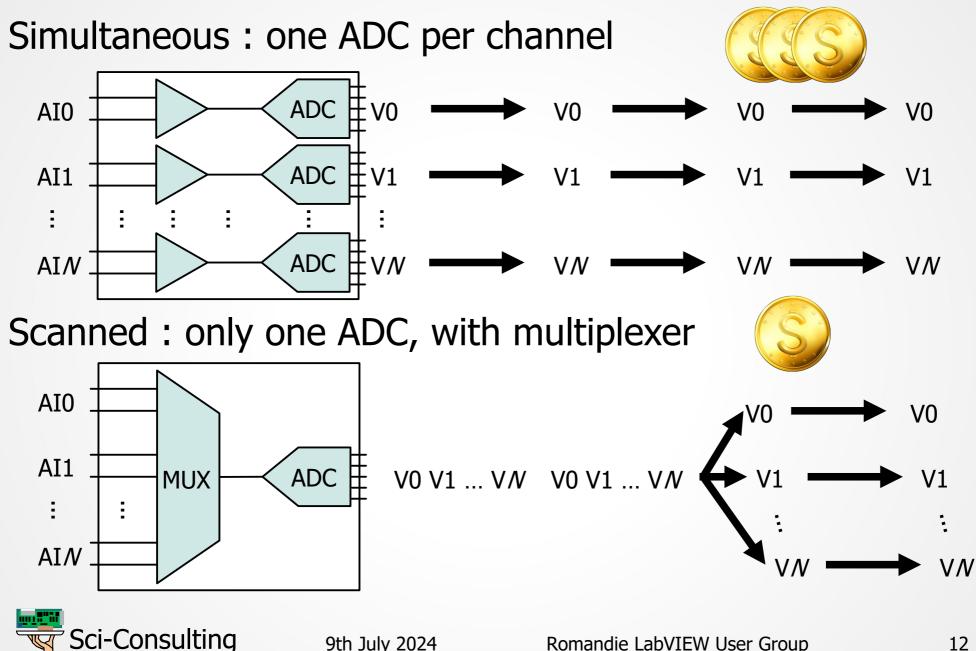
Simultaneous vs scanned



Scanned : only one ADC, with multiplexer Samples/s aggregate

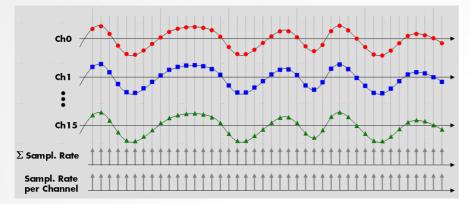


Simultaneous vs scanned



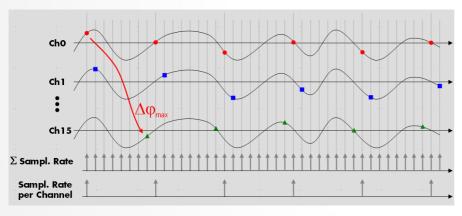
Simultaneous vs scanned

Simultaneous : channels sampled at same time

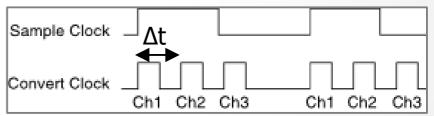


Sample Clock			
personal personal de la construcción de la construc	Ch1	Ch1	
	Ch2	Ch2	
	Ch3	Ch3	

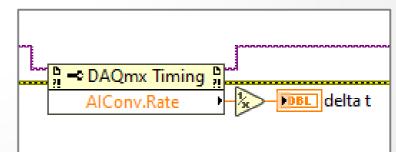
Scanned : channels not sampled at same time



NI 9205 : 250 kS/s, $\Delta t = 4 \mu s$ usually OK



but Δt is deterministic and known :





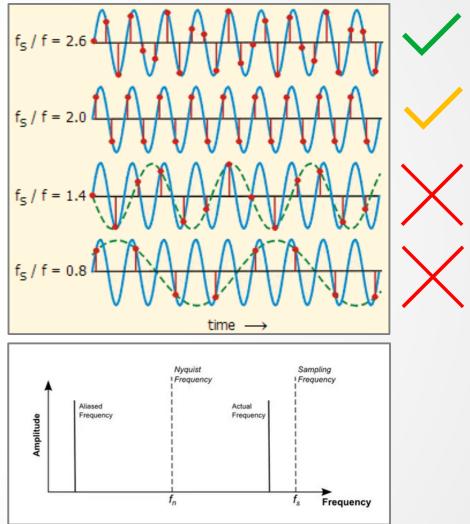
Nyquist–Shannon sampling theorem

We cannot analyze frequencies larger than $f_{sample}/2$, due to aliasing

NI 9205 250 kS/s 32 channels max

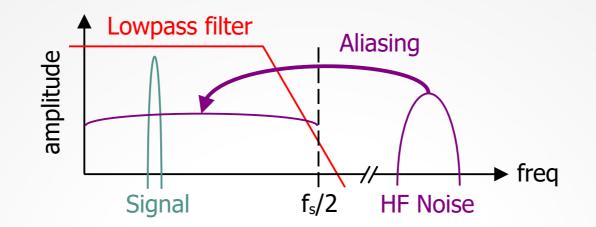
- 1 ch : FFT up to 125 kHz
- 12 ch : FFT limited to 10.4 kHz sampling 20.8 kS/s/ch

Simultaneous sampling devices do not "derate" with channel count





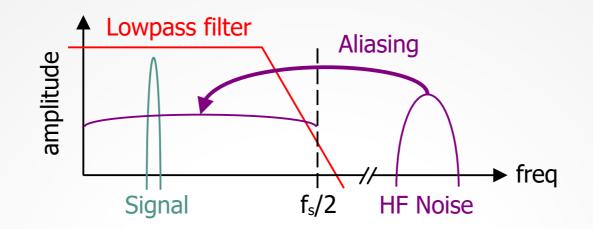
Nyquist–Shannon sampling theorem



Need to lowpass filter everything above f_s/2 Anti-aliasing filter

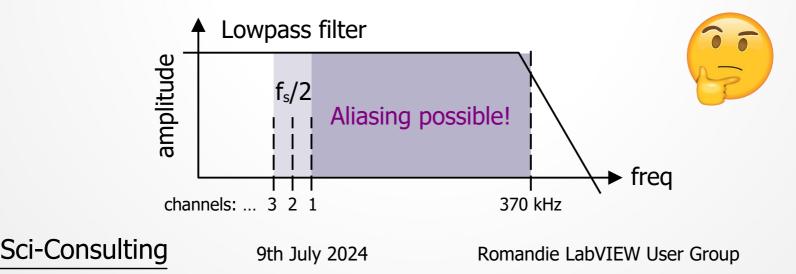


Nyquist–Shannon sampling theorem



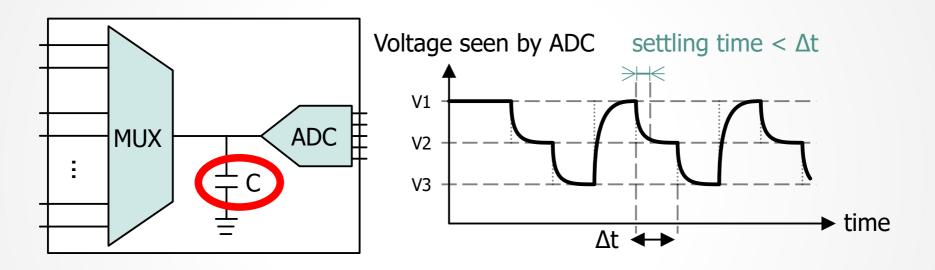
Need to lowpass filter everything above f_s/2 Anti-aliasing filter

NI 9205 sampling max 250 kS/s, $f_s/2 = 125$ kHz But from specifications: input bandwidth 370 kHz



Anti-aliasing filtering

Signal needs to settle fast enough at ADC despite parasitic capacitance C



Embedded anti-aliasing filter : • Simult

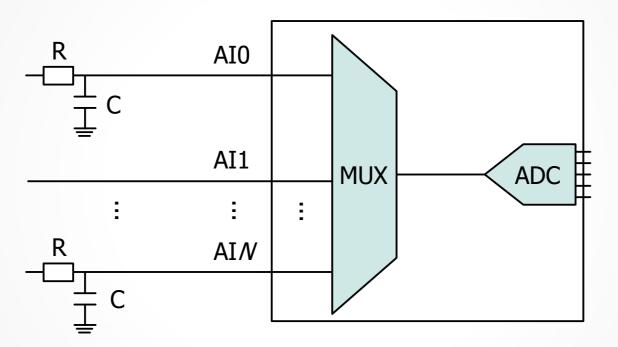
• Simultaneous

Scanned

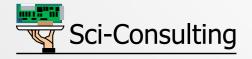


Anti-aliasing filtering

Let's place a simple external RC lowpass filter when needed !

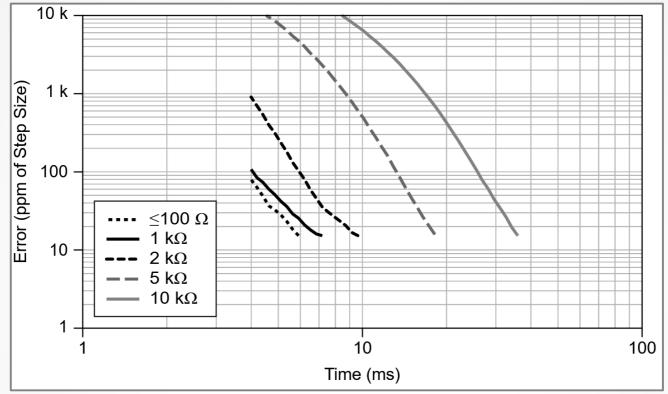


Problem solved ?



Signal impedance

Well... Example from NI 6221 specifications:



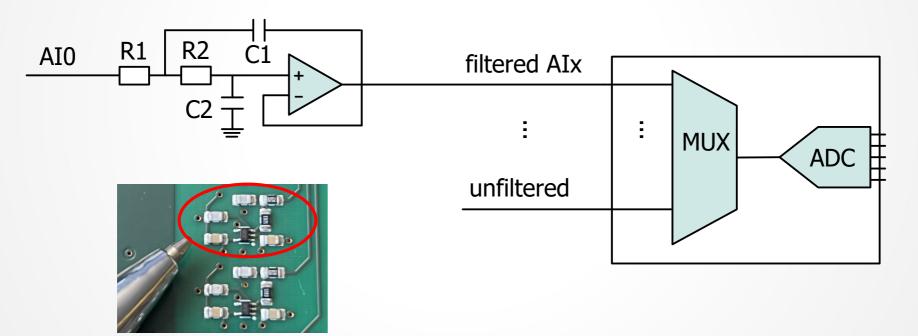
Signals with too high source impedance, such as voltage dividers and RC filters, cannot be reliably measured with scanned devices ! Symptoms : cross-talk



Anti-aliasing filtering

Need an external *active* lowpass filter to lower impedance

 Ex: Sallen-Key 2 poles Op-Amp to lower impedance, one per channel <u>when needed</u> (high impedance)





Optimization is project-specific

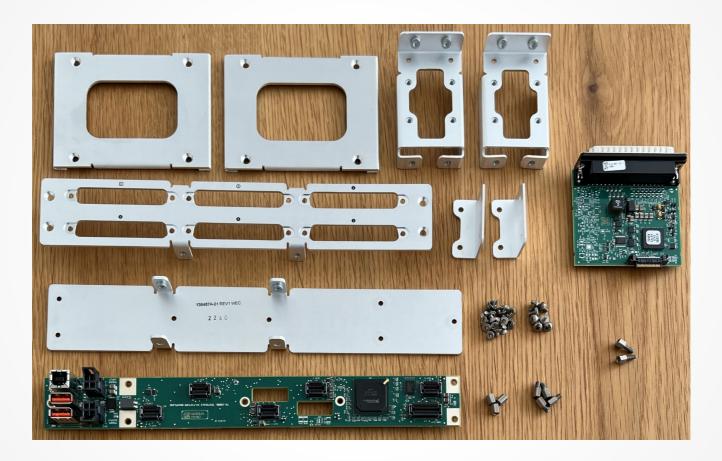
- Find best compromise between
 - → COTS hardware
 - Tailored adaptations only when needed
- Example built around a TestScale system :

U		Vout COM	AI 24 + - ±10	AI 25 + -		AI 26 + - ±1	AI 27		Al 0-23 : 4-20 mA	AI 28	AI 2	24V	Al 30 + - per selec	Al 31	24V 0V	DO 1 Power
	DUI 2	Vout Com	AI 0 AI 12 AI 24 AI 24 + - ±10	AI 1 AI 13 AI 25 + - DO V	Al 2 Al 14	Al 3 Al 15 Al 15 Al 26 + - ±1	Al 4 Al 16 Al 27 Al 27 + - 0 V	AI 5	Al 6	AI 7 AI 19 AI 28 AI 28 AI 28 AI 28 AI 28 AI 28 AI 28 AI 28	AI 8 AI 20 AI 20 AI 2 AI 2 AI 2 AI 2 AI 2	- V42	Al 10 Al 22 Al 30 Al 30 Al 30 Al 30 Al 30	AI 11 AI 23 AI 23 AI 31 AI 31 AI 31 AI 31 AI 31 AI 24 AI 31		DI 1 + © DO 1



NI TestScale platform

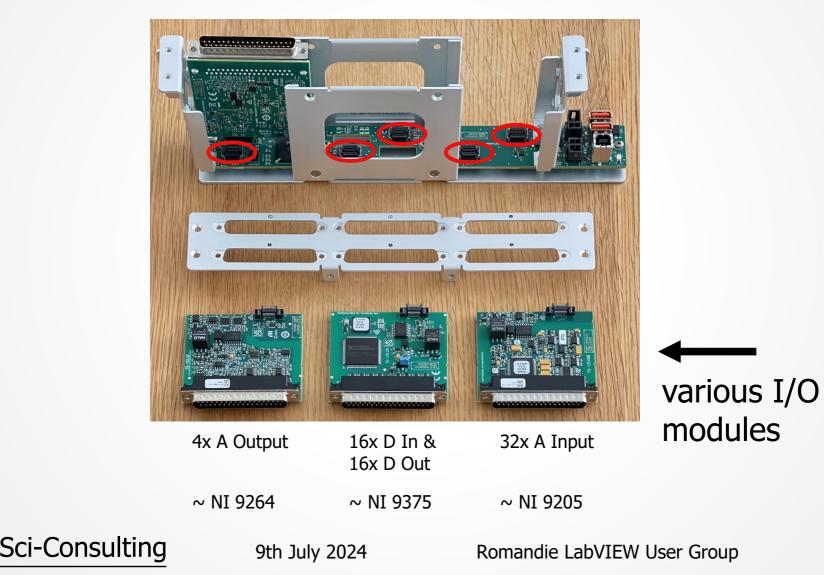
• Base kit : frame, backplane, Core module





NI TestScale platform

Assembled base kit, 5 slots for I/O modules



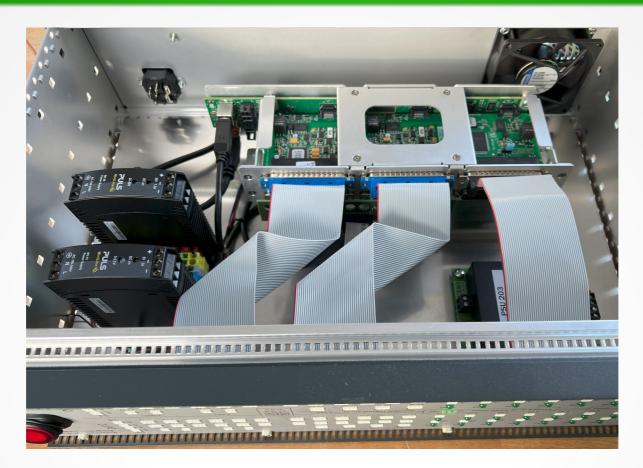
NI TestScale platform

- All modules have D-Sub 37 connectivity
- No specific signal conditioning (only ±10V analog and 5V digital)
- Backplane with USB and power in & out for daisy chaining



- System shown here : approx 2'500.- CHF 64 analog inputs, 8 analog outputs, 16 digital inputs, 16 digital outputs, 8 PFI
- Programmed with DAQmx, same features as a cDAQ system (counters, clocks, tasks, ...)

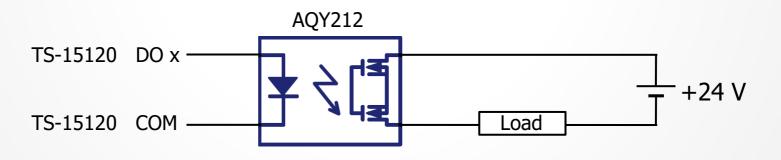


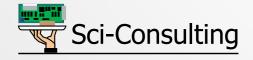


- Can be cost efficient, but needs some integration effort
- Not for single system, rather for minimal volume (not necessarily large though)



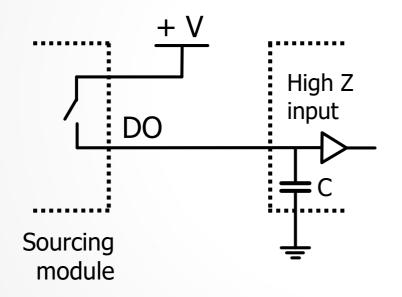
- TS-15100 analog input module is like NI 9205 : scanned 250 kS/s, ±10 V with gains
- Our system uses precision 200 Ω resistors for 4..20 mA signals, anti-aliasing filters
- TS-15120 (digital IO) is 5 V only, so signals converted to / from 24 V, also with optical isolation





 Digital output to high impedance "sink": think carefully about pull-up / pull-down if output is *switching* (and not *push-pull*)

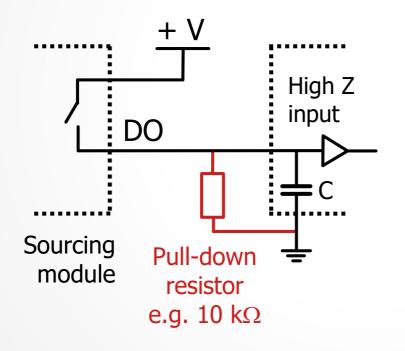






 Digital output to high impedance "sink": think carefully about pull-up / pull-down if output is *switching* (and not *push-pull*)



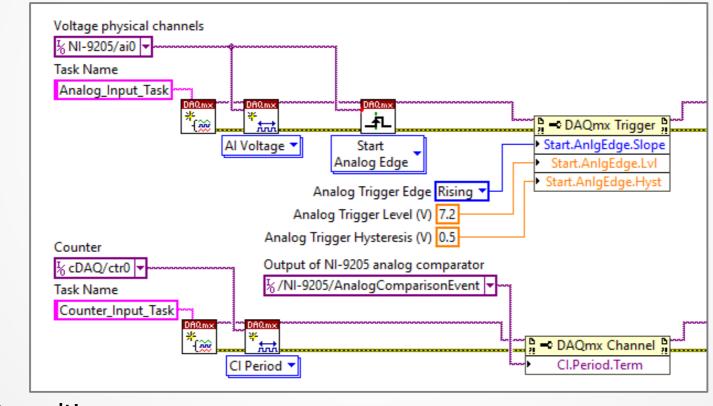


For **sinking** DO modules, use **pull-up** resistor to +V



Other topics

- Counters : Make smart use of them, very versatile !
- Counters usually work with 5V signals (PFI). But you can use this trick with APFI (X Series) or Analog comparison feature (NI 9205 or TS-15100) to use counters with analog signals (e.g. sine) with adjustable threshold just like 3rd party bench-top counters :





Thank you for following this presentation !

Questions ?

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